Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/642,534	JIN ET AL.	
Examiner	Art Unit	
Christopher A. Revak	2131	

SEARCHED					
Class	Subclass	Date	Examiner		
713	200-202	5/18/2005	CR		
709	223-225	5/18/2005	CR		
709	227,228	5/18/2005	CR		
709	238	5/18/2005	CR		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
713	200-202	5/18/2005	CR		
709	223-225	5/18/2005	CR		
709	227,228	5/18/2005	CR		
709/238		5/18/2005	CR		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	5/18/2005	CR
PALM Inventor Name Search	5/18/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	5/18/2005	CR